2.5 V / 3.3 V / 5.0 V 1:4 Clock Fanout Buffer

Description

The NB3L553 is a low skew 1-to 4 clock fanout buffer, designed for clock distribution in mind. The NB3L553 specifically guarantees low output-to-output skew. Optimal design, layout and processing minimize skew within a device and from device to device.

Features

- Input/Output Clock Frequency up to 200 MHz
- Low Skew Outputs (35 ps), Typical
- RMS Phase Jitter (12 kHz 20 MHz): 29 fs (Typical)
- Output goes to Three-State Mode via OE
- Operating Range: $V_{DD} = 2.375 \text{ V}$ to 5.25 V
- 5 V Tolerant Input Clock ICLK
- Ideal for Networking Clocks
- Packaged in 8-pin SOIC
- Industrial Temperature Range
- These are Pb-Free Devices

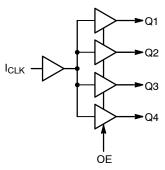


Figure 1. Block Diagram



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MARKING DIAGRAMS*



SOIC-8 D SUFFIX CASE 751



3L553 = Specific Device Code A = Assembly Location

L = Wafer Lot Y = Year W = Work Week ■ = Pb-Free Package



DFN8 MN SUFFIX CASE 506AA



6P = Specific Device Code

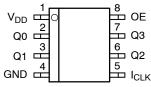
M = Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

*For additional marking information, refer to Application Note AND8002/D.

PINOUT DIAGRAM



ORDERING INFORMATION

| Device | Package | Shipping [†] |
|--------------|---------------------|-----------------------|
| NB3L553DG | SOIC-8 (Pb-Free) | 98 Units/Rail |
| NB3L553DR2G | SOIC-8 (Pb-Free) | 2500/Tape & Reel |
| NB3L553MNR4G | DFN-8 (Pb-Free) | 1000/Tape & Reel |

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Table 1. OE, OUTPUT ENABLE FUNCTION

| OE | Function |
|----|----------|
| 0 | Disable |
| 1 | Enable |

Table 2. PIN DESCRIPTION

| Pin # | Name | Туре | Description |
|-------|------------------|-------------------------|--|
| 1 | V_{DD} | Power | Positive supply voltage (2.375 V to 5.25 V) |
| 2 | Q0 | (LV)CMOS/(LV)TTL Output | Clock Output 0 |
| 3 | Q1 | (LV)CMOS/(LV)TTL Output | Clock Output 1 |
| 4 | GND | Power | Negative supply voltage; Connect to ground, 0 V |
| 5 | I _{CLK} | (LV)CMOS Input | Clock Input. 5.0 V tolerant |
| 6 | Q2 | (LV)CMOS/(LV)TTL Output | Clock Output 2 |
| 7 | Q3 | (LV)CMOS/(LV)TTL Output | Clock Output 3 |
| 8 | OE | (LV)TTL Input | V_{DD} for normal operation. Pin has no internal pullup or pull down resistor for open condition default. Use from 1 to 10 kOhms external resistor to force an open condition default state. |
| - | EP | Thermal Exposed Pad | (DFN8 only) Thermal exposed pad must be connected to a sufficient thermal conduit. Electrically connect to the most negative supply (GND) or leave unconnected, floating open. |

Table 3. MAXIMUM RATINGS

| Symbol | Parameter | Condition 1 | Condition 2 | Rating | Unit |
|------------------|---|------------------------|--|---|------|
| V _{DD} | Positive Power Supply | GND = 0 V | - | 6.0 | V |
| VI | Input Voltage | OE I _{CLK} | GND = 0 V and V _{DD} = 2.375 V to 5.25 V | $\begin{aligned} & \text{GND} - 0.5 \leq V_{\text{I}} \leq V_{\text{DD}} + 0.5 \\ & \text{GND} - 0.5 \leq V_{\text{I}} \leq 5.75 \end{aligned}$ | V |
| T _A | Operating Temperature Range, Industrial | - | - | ≥ -40 to ≤ +85 | °C |
| T _{stg} | Storage Temperature Range | - | - | -65 to +150 | °C |
| θJA | Thermal Resistance (Junction-to-Ambient) | 0 Ifpm 500 Ifpm | SOIC-8 | 190 130 | °C/W |
| θ _{JC} | Thermal Resistance (Junction-to-Case) | (Note 1) | SOIC-8 | 41 to 44 | °C/W |
| θ _{JA} | Thermal Resistance (Junction-to-Ambient) | 0 lfpm 500 lfpm | DFN8 DFN8 | 129 84 | °C/W |
| θЈС | Thermal Resistance (Junction-to-Case) | (Note 1) | DFN8 | 35 to 40 | °C/W |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. JEDEC standard multilayer board – 2S2P (2 signal, 2 power)

Table 4. ATTRIBUTES

| Chara | Characteristic | | | | |
|--|-----------------------------------|---------------------------|--|--|--|
| ESD Protection | Human Body Model Machine Model | > 2 kV > 150 V | | | |
| Moisture Sensitivity, Indefinite T | Level 1 | | | | |
| Flammability Rating | Oxygen Index: 28 to 34 | UL-94 code V-0 @ 0.125 in | | | |
| Transistor Count | | 531 Devices | | | |
| Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test | | | | | |

^{2.} For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 5. DC CHARACTERISTICS (V_{DD} = 2.375 V to 2.625 V, GND = 0 V, T_A = -40°C to +85°C) (Note 3)

| Symbol | Characteristic | Min | Тур | Max | Unit |
|-----------------------------------|--|--------------------------|------|--------------------------|------|
| I _{DD} | Power Supply Current @ 135 MHz, No Load | - | 25 | 30 | mA |
| V _{OH} | Output HIGH Voltage – I _{OH} = -16 mA | 1.7 | - | _ | V |
| V _{OL} | Output LOW Voltage – I _{OL} = 16 mA | - | - | 0.4 | V |
| V _{IH,} I _{CLK} | Input HIGH Voltage, I _{CLK} | (V _{DD} ÷2)+0.5 | - | 5.0 | V |
| V _{IL,} I _{CLK} | Input LOW Voltage, I _{CLK} | - | - | (V _{DD} ÷2)-0.5 | V |
| V _{IH,} OE | Input HIGH Voltage, OE | 1.8 | - | V_{DD} | V |
| V _{IL,} OE | Input LOW Voltage, OE | - | - | 0.7 | ٧ |
| ZO | Nominal Output Impedance | - | 20 | - | Ω |
| CIN | Input Capacitance, I _{CLK} , OE | - | 5.0 | - | pF |
| IOS | Short Circuit Current | - | ± 28 | - | mA |

DC CHARACTERISTICS (V_{DD} = 3.15 V to 3.45 V, GND = 0 V, T_A = -40° C to $+85^{\circ}$ C) (Note 3)

| Symbol | Characteristic | Min | Тур | Max | Unit |
|-----------------------------------|---|--------------------------|------|--------------------------|------|
| I _{DD} | Power Supply Current @ 135 MHz, No Load | - | 35 | 40 | mA |
| V _{OH} | Output HIGH Voltage – I _{OH} = -25 mA | 2.4 | - | - | ٧ |
| V _{OL} | Output LOW Voltage – I _{OL} = 25 mA | - | - | 0.4 | ٧ |
| V _{OH} | Output HIGH Voltage – I _{OH} = –12 mA (CMOS level) | V _{DD} – 0.4 | - | - | ٧ |
| V _{IH,} I _{CLK} | Input HIGH Voltage, I _{CLK} | (V _{DD} ÷2)+0.7 | - | 5.0 | ٧ |
| V _{IL,} I _{CLK} | Input LOW Voltage, I _{CLK} | - | - | (V _{DD} ÷2)-0.7 | ٧ |
| V _{IH,} OE | Input HIGH Voltage, OE | 2.0 | - | V_{DD} | ٧ |
| V _{IL,} OE | Input LOW Voltage, OE | 0 | _ | 0.8 | V |
| ZO | Nominal Output Impedance | _ | 20 | - | Ω |
| CIN | Input Capacitance, OE | _ | 5.0 | _ | pF |
| IOS | Short Circuit Current | _ | ± 50 | _ | mA |

DC CHARACTERISTICS (V_{DD} = 4.75 V to 5.25 V, GND = 0 V, T_A = $-40^{\circ}C$ to $+85^{\circ}C$) (Note 3)

| Symbol | Characteristic | Min | Тур | Max | Unit |
|-----------------------------------|---|--------------------------|------|--------------------------|------|
| I _{DD} | Power Supply Current @ 135 MHz, - No Load | - | 45 | 85 | mA |
| V _{OH} | Output HIGH Voltage – I _{OH} = –35 mA | 2.4 | - | - | V |
| V _{OL} | Output LOW Voltage – I _{OL} = 35 mA | - | - | 0.4 | ٧ |
| V _{OH} | Output HIGH Voltage – I _{OH} = –12 mA (CMOS level) | V _{DD} – 0.4 | - | - | V |
| V _{IH,} I _{CLK} | Input HIGH Voltage, I _{CLK} | (V _{DD} ÷2) + 1 | - | 5.0 | V |
| V _{IL,} I _{CLK} | Input LOW Voltage, I _{CLK} | - | - | (V _{DD} ÷2) – 1 | V |
| V _{IH,} OE | Input HIGH Voltage, OE | 2.0 | - | V_{DD} | V |
| V _{IL,} OE | Input LOW Voltage, OE | - | - | 0.8 | V |
| ZO | Nominal Output Impedance | - | 20 | - | Ω |
| CIN | Input Capacitance, OE | - | 5.0 | - | pF |
| IOS | Short Circuit Current | - | ± 80 | - | mA |

Table 6. AC CHARACTERISTICS; V_{DD} = 2.5 V ±5% (V_{DD} = 2.375 V to 2.625 V, GND = 0 V, T_A = -40°C to +85°C) (Note 3)

| Symbol | Characteristic | Min | Тур | Max | Unit |
|--------------------------------|---|-----|-----|-----|------|
| f _{in} | Input Frequency | _ | - | 200 | MHz |
| t _r /t _f | Output rise and fall times; 0.8 V to 2.0 V | - | 1.0 | 1.5 | ns |
| t _{pd} | Propagation Delay, CLK to Q _n (Note 4) | 2.2 | 3.0 | 5.0 | ns |
| t _{skew} | Output-to-output skew; (Note 5) | - | 35 | 50 | ps |
| t _{skew} | Device-to-device skew, (Note 5) | - | - | 500 | ps |

AC CHARACTERISTICS; V_{DD} = 3.3 V ±5% (V_{DD} = 3.15 V to 3.45 V, GND = 0 V, T_{A} = -40°C to +85°C) (Note 3)

| Symbol | Characteristic | Conditions | Min | Тур | Max | Unit |
|--------------------------------|---|--------------------------------|-----|-----|-----|------|
| f _{in} | Input Frequency | | - | - | 200 | MHz |
| t _{jitter} (φ) | RMS Phase Jitter (Integrated 12 kHz – 20 MHz) (See Figures 2 and 3) | f _{carrier} = 100 MHz | - | 18 | - | fs |
| t _r /t _f | Output rise and fall times; 0.8 V to 2.0 V | | - | 0.6 | 1.0 | ns |
| t _{pd} | Propagation Delay, CLK to Q _n (Note 4) | | 2.0 | 2.4 | 4.0 | ns |
| t _{skew} | Output-to-output skew; (Note 5) | | - | 35 | 50 | ps |
| t _{skew} | Device-to-device skew, (Note 5) | | ı | ı | 500 | ps |

$\textbf{AC CHARACTERISTICS; V}_{DD} = \textbf{5.0 V} \pm \textbf{5\%} \ (V_{DD} = 4.75 \ V \ to \ 5.25 \ V, \ GND = 0 \ V, \ T_{A} = -40 ^{\circ} C \ to \ +85 ^{\circ} C) \ (Note \ 3)$

| Symbol | Characteristic | Min | Min | Тур | Max | Unit |
|--------------------------------|---|--------------------------------|-----|-----|-----|------|
| f _{in} | Input Frequency | | - | = | 200 | MHz |
| t _{jitter} (φ) | RMS Phase Jitter (Integrated 12 kHz – 20 MHz) (See Figures 2 and 3) | f _{carrier} = 100 MHz | - | 29 | - | fs |
| t _r /t _f | Output rise and fall times; 0.8 V to 2.0 V | | - | 0.3 | 0.7 | ns |
| t _{pd} | Propagation Delay, CLK to Q _n (Note 4) | | 1.7 | 2.5 | 4.0 | ns |
| t _{skew} | Output-to-output skew; (Note 5) | | _ | 35 | 50 | ps |
| t _{skew} | Device-to-device skew, (Note 5) | | - | _ | 500 | ps |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 3. Outputs loaded with external $R_L = 33~\Omega$ series resistor and $C_L = 15~pF$ to GND. Duty cycle out = duty in. A 0.01 μ F decoupling capacitor should

be connected between V_{DD} and GND.

4. Measured with rail-to-rail input clock

^{5.} Measured on rising edges at $V_{DD} \div 2$ between any two outputs with equal loading.

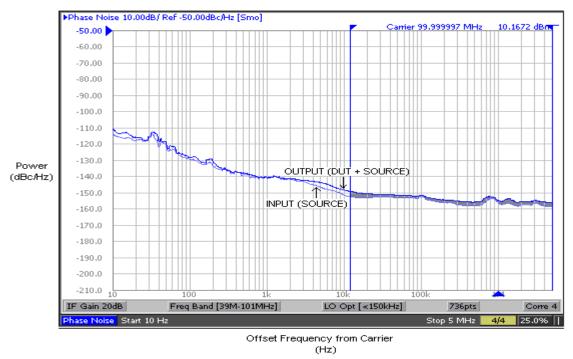


Figure 2. Phase Noise Plot at 100 MHz at an Operating Voltage of 3.3 V, Room Temperature

The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz; as shown in the shaded area) is 18 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 93.16 fs).

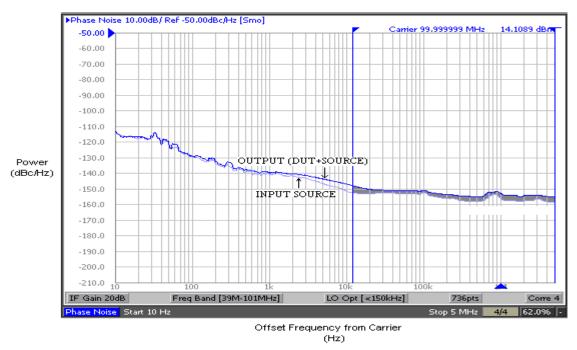
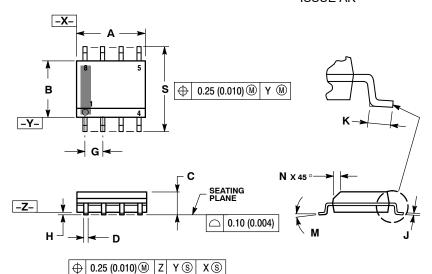


Figure 3. Phase Noise Plot at 100 MHz at an Operating Voltage of 5 V, Room Temperature

The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz; as shown in the shaded area) is 29 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 103.85 fs).

PACKAGE DIMENSIONS

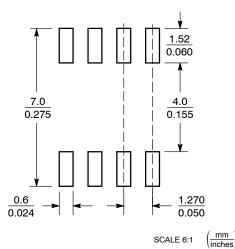
SOIC-8 NB CASE 751-07 **ISSUE AK**



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) DER SIDE
- 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
 5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
 6. 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751–07.

| | MILLIN | IETERS | INC | HES | |
|-----|--------|--------|-----------|-------|--|
| DIM | MIN | MAX | MIN | MAX | |
| Α | 4.80 | 5.00 | 0.189 | 0.197 | |
| В | 3.80 | 4.00 | 0.150 | 0.157 | |
| С | 1.35 | 1.75 | 0.053 | 0.069 | |
| D | 0.33 | 0.51 | 0.013 | 0.020 | |
| G | 1.27 | 7 BSC | 0.050 BSC | | |
| Н | 0.10 | 0.25 | 0.004 | 0.010 | |
| J | 0.19 | 0.25 | 0.007 | 0.010 | |
| K | 0.40 | 1.27 | 0.016 | 0.050 | |
| М | ° 0 | 8 ° | 0 ° | 8 ° | |
| N | 0.25 | 0.50 | 0.010 | 0.020 | |
| S | 5.80 | 6.20 | 0.228 | 0.244 | |

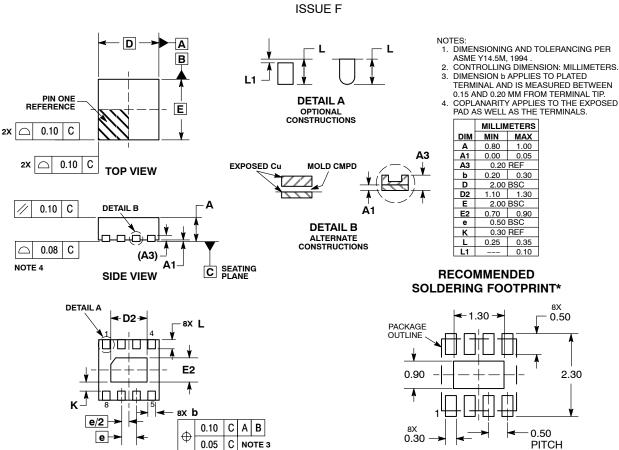
SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

DFN8 2x2, 0.5P CASE 506AA



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